

# Memory FeRAM

# 1M (128 K $\times$ 8) Bit SPI

# MB85RS1MT

#### **■ DESCRIPTION**

MB85RS1MT is a FeRAM (Ferroelectric Random Access Memory) chip in a configuration of 131,072 words  $\times$  8 bits, using the ferroelectric process and silicon gate CMOS process technologies for forming the nonvolatile memory cells.

MB85RS1MT adopts the Serial Peripheral Interface (SPI).

The MB85RS1MT is able to retain data without using a back-up battery, as is needed for SRAM. The memory cells used in the MB85RS1MT can be used for 10<sup>13</sup> read/write operations, which is a significant improvement over the number of read and write operations supported by Flash memory and E²PROM. MB85RS1MT does not take long time to write data like Flash memories or E²PROM, and MB85RS1MT takes no wait time.

#### **■ FEATURES**

• Bit configuration : 131,072 words × 8 bits

• Serial Peripheral Interface : SPI (Serial Peripheral Interface)

Correspondent to SPI mode 0 (0, 0) and mode 3 (1, 1)

• Operating frequency : 1.8 V to 2.7 V, 25 MHz (Max)

2.7 V to 3.6 V, 30 MHz (Max)

For FSTRD command 2.7 V to 3.6 V, 40 MHz (Max)

• High endurance : 10<sup>13</sup> times / byte

Data retention
 : 10 years (+85 °C), 95 years (+55 °C), over 200 years (+35 °C)

Operating power supply voltage : 1.8 V to 3.6 V

Low power consumption : Operating power supply current 9.5 mA (Max@30 MHz)

Standby current 120 μA (Max) Sleep current 10 μA (Max)

• Operation ambient temperature range : -40 °C to +85 °C

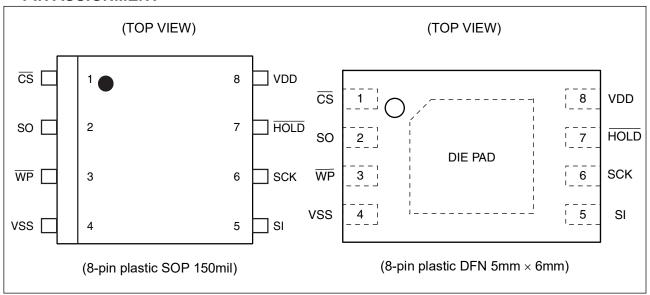
• Package : 8-pin plastic SOP 150mil

8-pin plastic DFN 5mm × 6mm

RoHS compliant

Fujitsu Semiconductor Memory Solutions Limited has changed its name to RAMXEED Limited. RAMXEED Limited will continue to offer and support existing products while maintaining Fujitsu's part number unchanged.

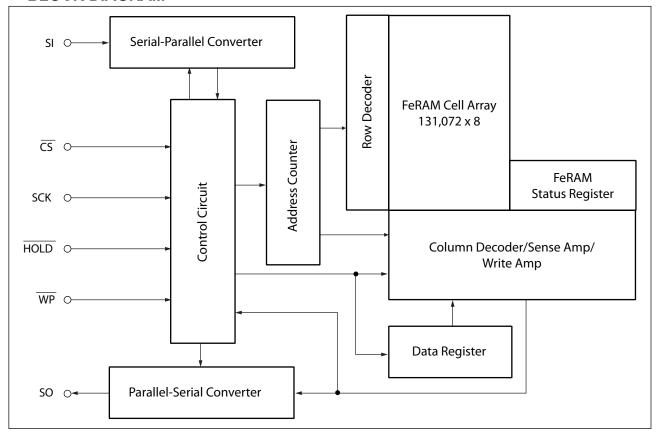
# **■ PIN ASSIGNMENT**



## **■ PIN FUNCTIONAL DESCRIPTIONS**

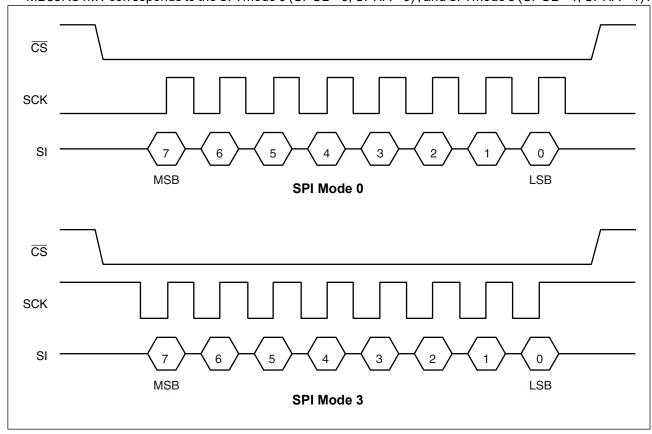
Pin No.	Pin Name	Functional description
1	<del>CS</del>	Chip Select pin This is an input pin to make chips select. When $\overline{CS}$ is "H" level, device is in deselect (standby) status and SO becomes High-Z. Inputs from other pins are ignored for this time. When $\overline{CS}$ is "L" level, device is in select (active) status. $\overline{CS}$ has to be "L" level before inputting op-code. The Chip Select pin is pulled up internally to the VDD pin.
3	WP	Write Protect pin This is a pin to control writing to a status register. The writing of status register (see "■ STATUS REGISTER") is protected in related with WP and WPEN. See "■WRITING PROTECT" for detail.
7	HOLD	Hold pin  This pin is used to interrupt serial input/output without making chips deselect. When HOLD is "L" level, hold operation is activated, SO becomes High-Z, SCK and SI become do not care. See "■ HOLD OPERATION" for detail.
6	SCK	Serial Clock pin This is a clock input pin to input/output serial data. SI is loaded synchronously to a rising edge, SO is output synchronously to a falling edge.
5	SI	Serial Data Input pin This is an input pin of serial data. This inputs op-code, address, and writing data.
2	SO	Serial Data Output pin This is an output pin of serial data. Reading data of FeRAM memory cell array and status register data are output. This is High-Z during standby.
8	VDD	Supply Voltage pin
4	VSS	Ground pin
DIE PAD	_	It is allowed for the DIE PAD on the bottom of the DFN8 package to be floating (no connection to anything) or to be connected to VSS.

# ■ BLOCK DIAGRAM



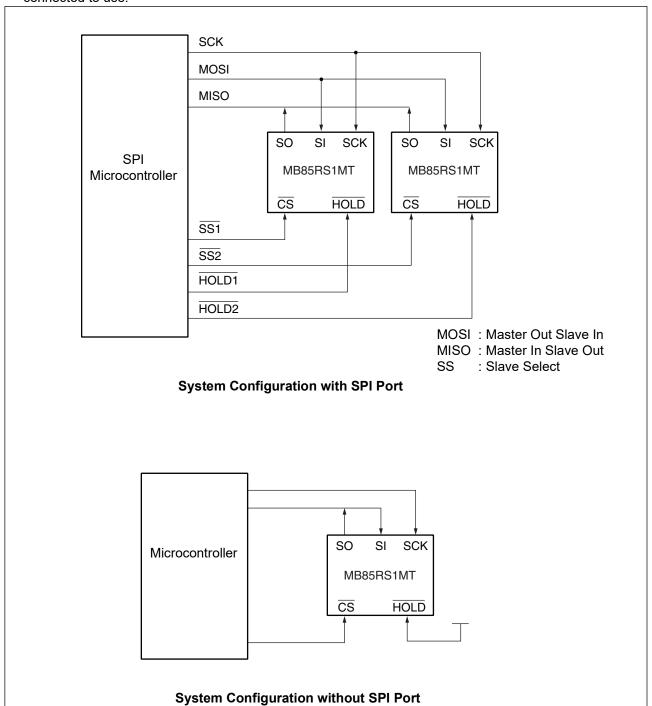
## ■ SPI MODE

MB85RS1MT corresponds to the SPI mode 0 (CPOL = 0, CPHA = 0), and SPI mode 3 (CPOL = 1, CPHA = 1).



# ■ SERIAL PERIPHERAL INTERFACE (SPI)

MB85RS1MT works as a slave of SPI. More than 2 devices can be connected by using microcontroller equipped with SPI port. By using a microcontroller not equipped with SPI port, SI and SO can be bus connected to use.



## **■ STATUS REGISTER**

Bit No.	Bit Name	Function
7	WPEN	Status Register Write Protect This is a bit composed of nonvolatile memories (FeRAM). WPEN protects writing to a status register (refer to " WRITING PROTECT") relating with WP input. Writing with the WRSR command and reading with the RDSR command are possible.
6 to 4	_	Not Used Bits These are bits composed of nonvolatile memories, writing with the WRSR command is possible. These bits are not used but they are read with the RDSR command.
3	BP1	Block Protect This is a bit composed of nonvolatile memory. This defines size of write
2	BP0	protect block for the WRITE command (refer to " ■BLOCK PROTECT"). Writing with the WRSR command and reading with the RDSR command are possible.
1	WEL	Write Enable Latch This indicates FeRAM Array and status register are writable. The WREN command is for setting, and the WRDI command is for resetting. With the RDSR command, reading is possible but writing is not possible with the WRSR command. WEL is reset after the following operations.  After power ON. After WRDI command recognition. The rising edge of CS after WRSR command recognition. The rising edge of CS after WRITE command recognition. After return from SLEEP mode.
0	0	This is a bit fixed to "0".

## ■ OP-CODE

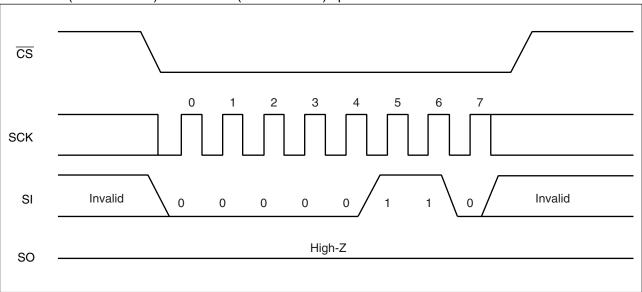
MB85RS1MT accepts 9 kinds of command specified in op-code. Op-code is a  $\underline{\text{co}}$ de composed of 8 bits shown in the table below. Do not input invalid codes other than those codes. If  $\overline{\text{CS}}$  is risen while inputting op-code, the command are not performed.

Name	Description	Op-code
WREN	Set Write Enable Latch	0000 0110в
WRDI	Reset Write Enable Latch	0000 0100в
RDSR	Read Status Register	0000 0101в
WRSR	Write Status Register	0000 0001в
READ	Read Memory Code	0000 0011в
WRITE	Write Memory Code	0000 0010в
RDID	Read Device ID	1001 1111в
FSTRD	Fast Read Memory Code	0000 1011в
SLEEP	Sleep Mode	1011 1001в

#### **■ COMMAND**

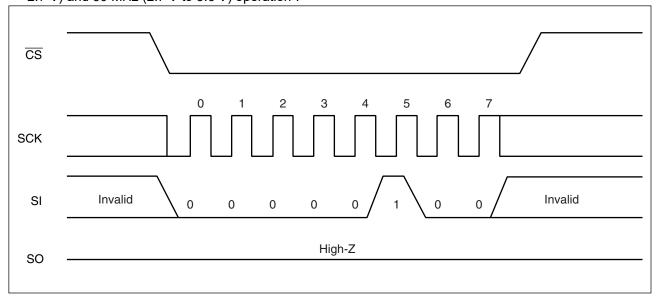
#### • WREN

The WREN command sets WEL (Write Enable Latch). WEL has to be set with the WREN command before writing operation (WRSR command and WRITE command). WREN command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



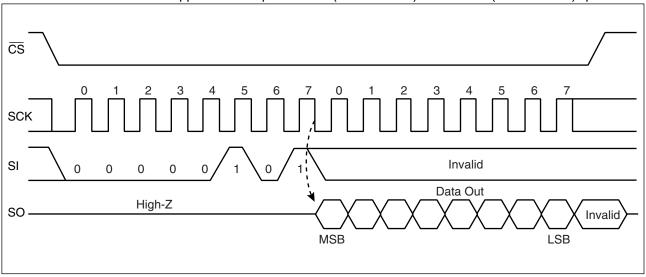
#### WRDI

The WRDI command resets WEL (Write Enable Latch) . Writing operation (WRSR command and WRITE command) are not performed when WEL is reset. WRDI command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



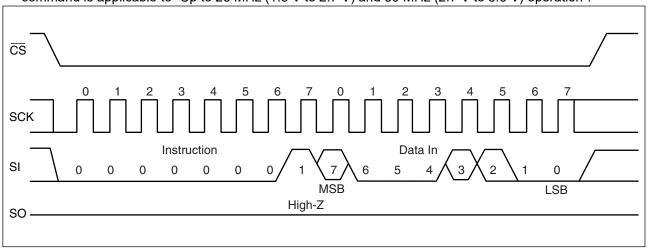
#### • RDSR

The RDSR command reads status register data. After op-code of RDSR is input to SI, 8-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. In the RDSR command, repeated reading of status register is enabled by sending SCK continuously before rising of CS. RDSR command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



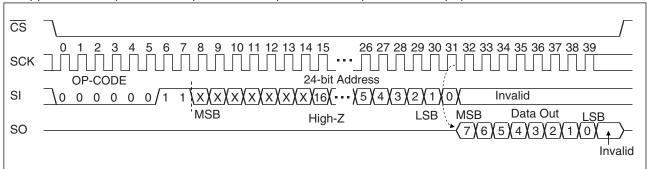
#### • WRSR

The WRSR command writes data to the nonvolatile memory bit of status register. After performing WRSR op-code to a SI pin, 8 bits writing data is input. WEL (Write Enable Latch) is not able to be written with WRSR command. A SI value correspondent to bit 1 is ignored. Bit <u>0</u> of the status register is fixed to "0" and cannot be written. The SI value corresponding to bit <u>0</u> is ignored. WP signal level shall be fixed before performing WRSR command, and do not change the WP signal level until the end of command sequence. WRSR command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



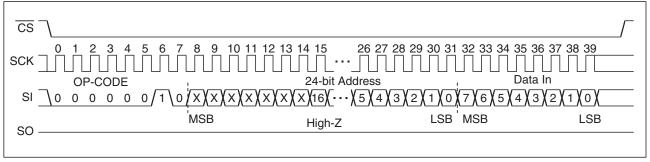
#### • READ

The READ command reads FeRAM memory cell array data. Arbitrary 24 bits address and op-code of READ are input to SI. The 7-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When  $\overline{\text{CS}}$  is risen, the READ command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before  $\overline{\text{CS}}$  rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely. READ command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



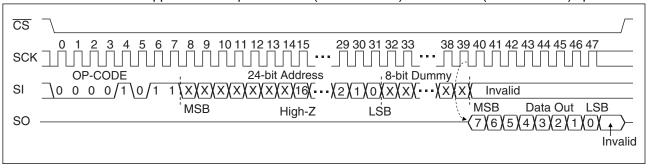
#### WRITE

The WRITE command writes data to FeRAM memory cell array. WRITE op-code, arbitrary 24 bits of address and 8 bits of writing data are input to SI. The 7-bit upper address bit is invalid. When 8 bits of writing data is input, data is written to FeRAM memory cell array. Risen  $\overline{\text{CS}}$  will terminate the WRITE command, but if you continue sending the writing data for 8 bits each before  $\overline{\text{CS}}$  rising, it is possible to continue writing with automatic address increment. When it reaches the most significant address, it rolls over to the starting address, and writing cycle can be continued infinitely. WRITE command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



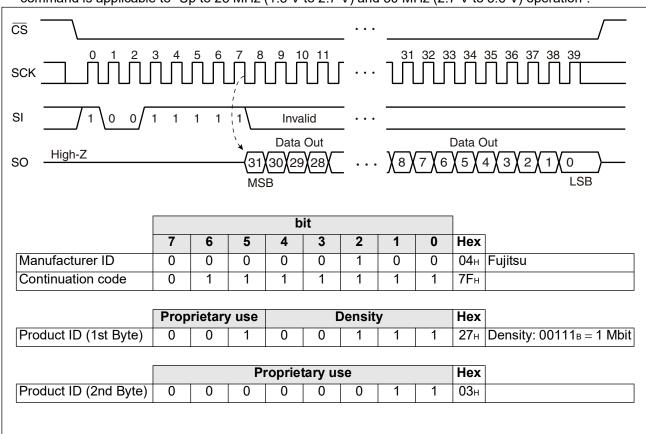
#### • FSTRD

The FSTRD command reads FeRAM memory cell array data. Arbitrary 24 bits address and op-code of FSTRD are input to SI followed by 8 bits dummy. The 7-bit upper address bit is invalid. Then, 8-cycle clock is input to SCK. SO is output synchronously to the falling edge of SCK. While reading, the SI value is invalid. When  $\overline{CS}$  is risen, the FSTRD command is completed, but keeps on reading with automatic address increment which is enabled by continuously sending clocks to SCK in unit of 8 cycles before  $\overline{CS}$  rising. When it reaches the most significant address, it rolls over to the starting address, and reading cycle keeps on infinitely. FSTRD command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 40 MHz (2.7 V to 3.6 V) operation".



#### • RDID

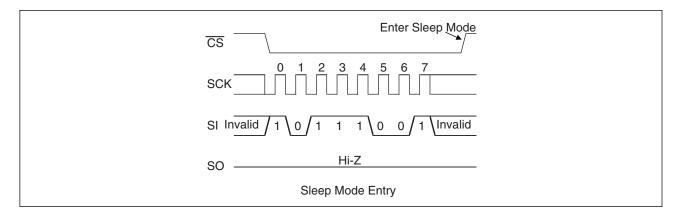
The RDID command reads fixed Device ID. After performing RDID op-code to SI, 32-cycle clock is input to SCK. The SI value is invalid for this time. SO is output synchronously to a falling edge of SCK. The output is in order of Manufacturer ID (8bit)/Continuation code (8bit)/Product ID (1st Byte)/Product ID (2nd Byte). In the RDID command, SO holds the output state of the last bit in 32-bit Device ID until  $\overline{CS}$  is risen. RDID command is applicable to "Up to 25 MHz (1.8 V to 2.7 V) and 30 MHz (2.7 V to 3.6 V) operation".



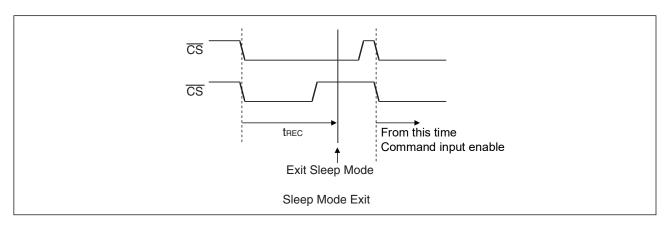
#### • SLEEP

The SLEEP command shifts the LSI to a low power mode called "SLEEP mode". The transition to the SLEEP mode is carried out at the rising edge of  $\overline{CS}$  after operation code in the SLEEP command. However, when at least one SCK clock is inputted before the rising edge of  $\overline{CS}$  after operation code in the SLEEP command, this SLEEP command is canceled.

After the SLEEP mode transition, SCK and SI inputs are logically ignored and SO changes to a Hi-Z state. If input pin(s) other than  $\overline{CS}$  pin is (are) not fixed to VSS or VDD, flow-throw current may flow.



Returning to an normal operation from the SLEEP mode is carried out after  $t_{REC}$  (Max 400  $\mu$ s) time from the falling edge of  $\overline{CS}$  (see the figure below). It is possible to return  $\overline{CS}$  to H level before  $t_{REC}$  time. However, it is prohibited to bring down  $\overline{CS}$  to L level again during  $t_{REC}$  period.



#### **■ BLOCK PROTECT**

Writing protect block for WRITE command is configured by the value of BP0 and BP1 in the status register.

BP1	BP0	Protected Block
0	0	None
0	1	18000н to 1FFFFн (upper 1/4)
1	0	10000н to 1FFFFн (upper 1/2)
1	1	00000н to 1FFFFн (all)

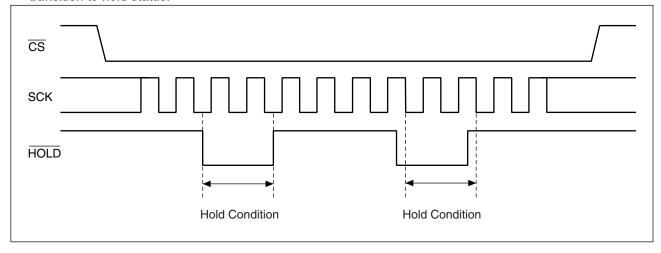
#### **■ WRITING PROTECT**

Writing operation of the WRITE command and the WRSR command are protected with the value of WEL, WPEN, WP as shown in the table.

WEL	WPEN	WP	Protected Blocks	Unprotected Blocks	Status Register
0	Х	Х	Protected	Protected	Protected
1	0	Х	Protected	Unprotected	Unprotected
1	1	0	Protected	Unprotected	Protected
1	1	1	Protected	Unprotected	Unprotected

#### **■ HOLD OPERATION**

Hold status is retained without aborting a command if HOLD is "L" level while  $\overline{CS}$  is "L" level. The timing for starting and ending hold status depends on the SCK to be "H" level or "L" level when a HOLD pin input is transited to the hold condition as shown in the diagram below. In case the HOLD pin transited to "L" level when SCK is "L" level, return the HOLD pin to "H" level at SCK being "L" level. In the same manner, in case the HOLD pin transited to "L" level when SCK is "H" level, return the HOLD pin to "H" level at SCK being "H" level. Arbitrary command operation is interrupted in hold status, SCK and SI inputs become do not care. And, SO becomes High-Z while reading command (RDSR, READ). If  $\overline{CS}$  is rising during hold status, a command is aborted. In case the command is aborted before its recognition, WEL holds the value before transition to hold status.



#### ■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Ra	Unit	
Farameter	Symbol	Min	Max	Oilit
Power supply voltage*	V <sub>DD</sub>	- 0.5	+ 4.0	V
Input voltage*	Vin	- 0.5	$V_{DD} + 0.5 (\le 4.0 V)$	V
Output voltage*	Vоит	- 0.5	$V_{DD} + 0.5 ( \le 4.0 V)$	V
Operation ambient temperature	TA	- 40	+ 85	°C
Storage temperature	Tstg	<b>– 55</b>	+ 125	°C

<sup>\*:</sup> These parameters are based on the condition that Vss is 0 V.

WARNING: Semiconductor devices may be permanently damaged by application of stress (including, without limitation, voltage, current or temperature) in excess of absolute maximum ratings. Do not exceed any of these ratings.

#### **■ RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol		Unit		
Parameter	Symbol	Min	Тур	Max	Offic
Power supply voltage*1	V <sub>DD</sub>	1.8	3.3	3.6	V
Operation ambient temperature*2	TA	- 40	_	+ 85	°C

<sup>\*1:</sup> These parameters are based on the condition that Vss is 0 V.

WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated under these conditions.

Any use of semiconductor devices will be under their recommended operating condition. Operation under any conditions other than these conditions may adversely affect reliability of device and could result in device failure.

No warranty is made with respect to any use, operating conditions or combinations not represented on this data sheet. If you are considering application under any conditions other than listed herein, please contact sales representatives beforehand.

<sup>\*2:</sup> Ambient temperature when only this device is working. Please consider it to be the almost same as the package surface temperature.

# **■ ELECTRICAL CHARACTERISTICS**

# 1. DC Characteristics

(within recommended operating conditions)

Parameter	Symbol Condition —			Unit			
Parameter	Symbol	Condition	Min	Тур	Max	Unit	
		$0 \le \overline{CS} < V_{DD}$		_	200		
Input leakage current*1	  Iu	$\overline{CS} = V_{DD}$			1	μΑ	
, , , , , , , , , , , , , , , , , , ,	11	$\overline{WP}$ , $\overline{HOLD}$ , SCK SI = 0 V to V <sub>DD</sub>			1	pu ·	
Output leakage current*2	ILO	SO = 0 V to V <sub>DD</sub>			1	μΑ	
		SCK = 1 MHz		0.77	_	mA	
Operating power supply current	Поо	SCK = 10 MHz		2.3	_	mA	
Operating power supply current		SCK = 25 MHz		4.85	_	mA	
		SCK = 30 MHz		5.7	9.5	mA	
Standby current	Isa	$SCK = SI = \overline{CS} = V_{DD}$		25	120	μΑ	
Sleep current	Izz	$\overline{CS} = V_{DD}$ All inputs Vss or V <sub>DD</sub>	_	_	10	μА	
Input high voltage	ViH	$V_{DD} = 1.8 \text{ V to } 3.6 \text{ V}$	$V_{\text{DD}} \times 0.7$		V <sub>DD</sub> + 0.5	V	
Input low voltage	VIL	$V_{DD} = 1.8 \text{ V to } 3.6 \text{ V}$	- 0.5	_	$V_{DD} \times 0.3$	V	
Output high voltage	Vон	Iон = − 2 mA	V <sub>DD</sub> - 0.5	_	_	V	
Output low voltage	Vol	IoL = 2 mA		_	0.4	V	
Pull up resistance for CS	R₽	_	18	33	80	kΩ	

<sup>\*1 :</sup> Applicable pin :  $\overline{\text{CS}}$ ,  $\overline{\text{WP}}$ ,  $\overline{\text{HOLD}}$ , SCK, SI

<sup>\*2 :</sup> Applicable pin : SO

#### 2. AC Characteristics

		Value					
Parameter	Symbol		z operation*¹ V to 2.7 V)	Up to 30 MH (V <sub>DD</sub> = 2.7	Unit		
		Min	Max	Min	Max		
SCK clock frequency (All commands except FST- RD command)	fск	0	25	0	30	MHz	
SCK clock frequency (for FSTRD command)	fск	0	25	0	40	MHz	
Clock high time	tсн	15		11		ns	
Clock low time	<b>t</b> cL	15		11	_	ns	
Chip select set up time	<b>t</b> csu	10	_	10	_	ns	
Chip select hold time	<b>t</b> csн	10	_	10	_	ns	
Output disable time	tod	_	12		12	ns	
Output data valid time	todv	_	18	_	9	ns	
Output hold time	tон	0	_	0	_	ns	
Deselect time	t₀	40	_	40	_	ns	
Data in rising time	t <sub>R</sub>	_	50	_	50	ns	
Data falling time	t⊧	_	50	_	50	ns	
Data set up time	<b>t</b> su	5		5		ns	
Data hold time	tн	5	_	5	_	ns	
HOLD set uptime	<b>t</b> HS	10		10		ns	
HOLD hold time	tнн	10		10		ns	
HOLD output floating time	<b>t</b> HZ	_	20	_	20	ns	
HOLD output active time	<b>t</b> LZ		20		20	ns	
SLEEP recovery time	trec		400		400	μS	

<sup>\*1 :</sup> All commands except FSTRD are applicable to "Up to 25 MHz operation" in  $V_{DD} = 1.8 \text{ V}$  to 2.7 V.

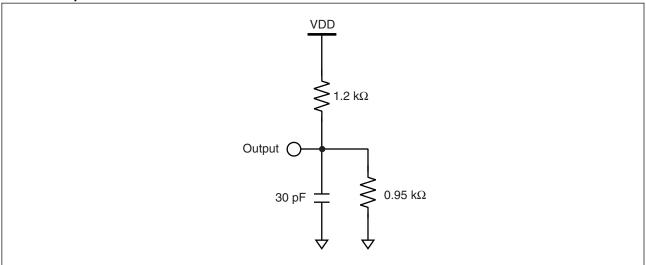
#### **AC Test Condition**

 $\begin{array}{lll} \mbox{Power supply voltage} & : 1.8 \ \mbox{V to } 3.6 \ \mbox{V} \\ \mbox{Operation ambient temperature} & : -40 \ \mbox{°C to } +85 \ \mbox{°C} \\ \mbox{Input voltage magnitude} & : \mbox{V}_{DD} \times 0.7 \le \mbox{V}_{IH} \le \mbox{V}_{DD} \\ & 0 \le \mbox{V}_{IL} \le \mbox{V}_{DD} \times 0.3 \end{array}$ 

Input rising time : 5 ns
Input falling time : 5 ns
Input judge level : VDD/2
Output judge level : VDD/2

<sup>\*2 :</sup> All commands except FSTRD are applicable to "Up to 30 MHz operation" in  $V_{\text{DD}} = 2.7 \text{ V}$  to 3.6 V.

# **AC Load Equivalent Circuit**

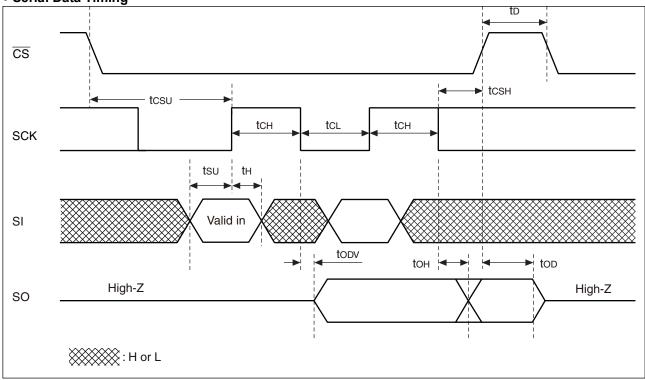


# 3. Pin Capacitance

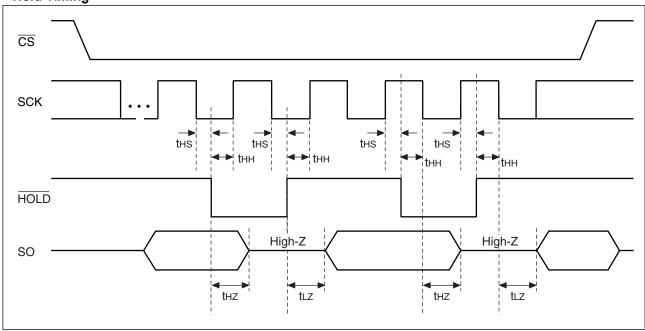
Parameter	Symbol	Condition	Va	Unit	
Parameter	Syllibol	Condition	Min	Max	
Output capacitance	Со	$V_{DD} = V_{IN} = V_{OUT} = 0 V$ ,	_	8	pF
Input capacitance	Cı	f = 1 MHz, T <sub>A</sub> = +25 °C	_	6	pF

# **■ TIMING DIAGRAM**

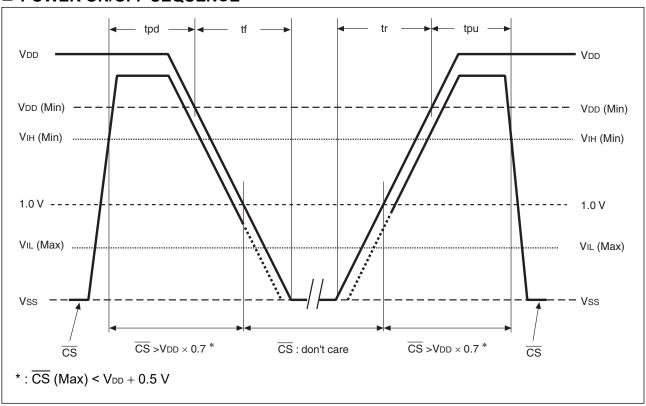
# • Serial Data Timing



# • Hold Timing



#### **■ POWER ON/OFF SEQUENCE**



Parameter	Symbol	Va	Unit	
Farameter	Symbol	Min	Max	Offic
CS level hold time at power OFF	tpd	400	_	ns
CS level hold time at power ON	tpu	250		μS
Power supply rising time	tr	0.05		ms/V
Power supply falling time	tf	0.1	_	ms/V

If the device does not operate within the specified conditions of read cycle, write cycle or power on/off sequence, memory data can not be guaranteed.

### **■ Feram Characteristics**

Item	Min	Max	Unit	Parameter
Read/Write Endurance*1	10 <sup>13</sup>		Times/byte	Endurance of the sum of read counts and write counts. Operation Ambient Temperature $T_A = +85  ^{\circ}\text{C}$
	10			Operation Ambient Temperature T <sub>A</sub> = +85 °C
Data Retention*2	95	_	Years	Operation Ambient Temperature T <sub>A</sub> = + 55 °C
	≥ 200			Operation Ambient Temperature T <sub>A</sub> = + 35 °C

<sup>\*1 :</sup> Total number of reading and writing defines the minimum value of endurance, as an FeRAM memory operates with destructive readout mechanism.

<sup>\*2 :</sup> Minimum values define retention time of the first reading/writing data right after shipment, and these values are calculated by qualification results.

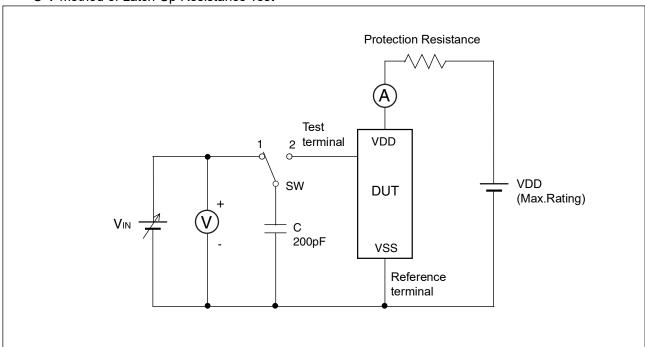
#### ■ NOTE ON USE

We recommend programming of the device after reflow. Data written before reflow cannot be guaranteed.

# **■ ESD AND LATCH-UP**

Test	DUT	Value
ESD HBM (Human Body Model) JESD22-A114 compliant	MB85RS1MTPNF-G-JNE1 MB85RS1MTPNF-G-AWE2	≥  2000 V
ESD CDM (Charged Device Model) JESD22-C101 compliant	MB85RS1MTPNF-G-JNERE1 MB85RS1MTPNF-G-AWERE2 MB85RS1MTPNF-G-AMERE2	≥  1000 V
Latch-Up (C-V Method) Proprietary method	MB85RS1MTPNF-G-AME2 MB85RS1MTPNF-G-AWEWE1	≥  200 V

#### • C-V method of Latch-Up Resistance Test



Note: Charge voltage alternately switching 1 and 2 approximately 2 sec interval. This switching process is considered as one cycle. Repeat this process 5 times. However, if the latch-up condition occurs before completing 5times, this test must be stopped immediately.

#### ■ REFLOW CONDITIONS AND FLOOR LIFE

[ JEDEC MSL ]: Moisture Sensitivity Level 3 (IPC/JEDEC J-STD-020E)

#### ■ Current status on Contained Restricted Substances

This product complies with the regulations of REACH Regulations, EU RoHS Directive and China RoHS.

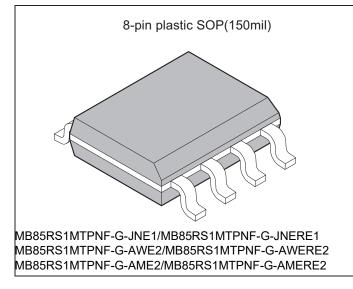
# ■ ORDERING INFORMATION

Part number	Package	Shipping form	Minimum shipping quantity
MB85RS1MTPNF-G-JNE1	8-pin plastic SOP	Tube	*1
MB85RS1MTPNF-G-AWE2	8-pin plastic SOP	Tube	*1
MB85RS1MTPNF-G-JNERE1	8-pin plastic SOP	Embossed Carrier tape	1500
MB85RS1MTPNF-G-AWERE2	8-pin plastic SOP	Embossed Carrier tape	1500
MB85RS1MTPNF-G-AMERE2	8-pin plastic SOP	Embossed Carrier tape	1500
MB85RS1MTPNF-G-AME2	8-pin plastic SOP	Tray	*1
MB85RS1MTPN-G-AWEWE1	8-pin plastic DFN	Embossed Carrier tape	1500

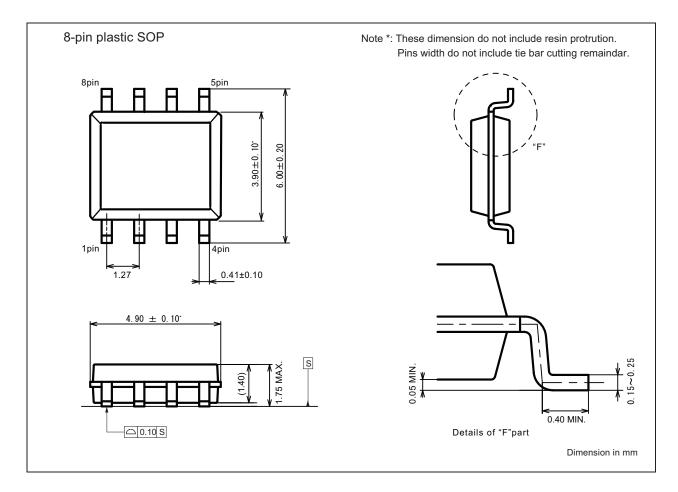
<sup>\*1 :</sup> Please contact our sales office about minimum shipping quantity.

### **■ PACKAGE DIMENSION**

(1)MB85RS1MTPNF-G-JNE1/MB85RS1MTPNF-G-JNERE1 MB85RS1MTPNF-G-AWE2/MB85RS1MTPNF-G-AWERE2 MB85RS1MTPNF-G-AME2/MB85RS1MTPNF-G-AMERE2

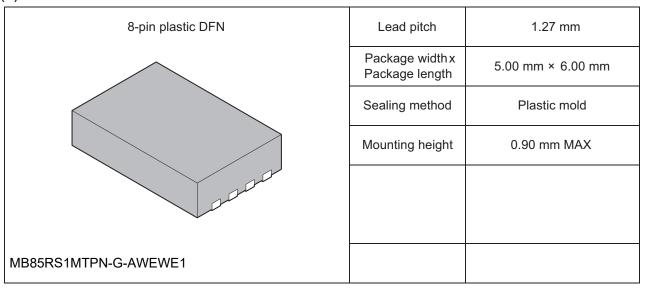


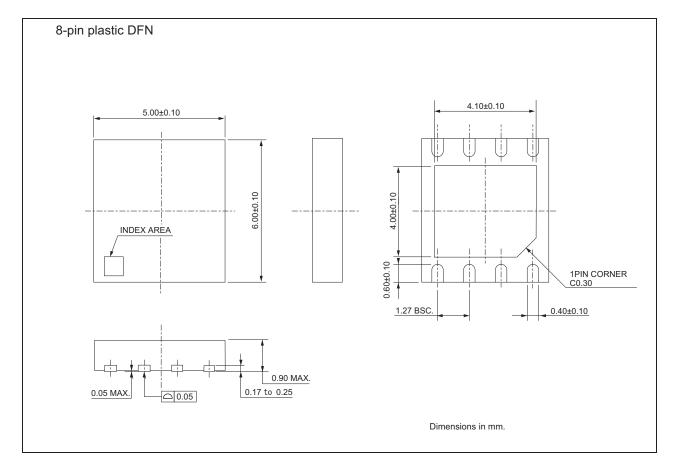
Lead pitch	1.27mm
Package width x Package length	3.90mm x 4.90mm
Lead shape	Gullwing
Sealing method	Plastic mold
Mounting height	1.75mm MAX.



## (Continued)

# (2)MB85RS1MTPN-G-AWEWE1





# **■ MARKING (Example)**

[MB85RS1MTPNF-G-JNE1] [MB85RS1MTPNF-G-JNERE1]

# RS1MT E11900 300

[8-pin plastic SOP 150mil]

RS1MT: Product name

E11900: E1(Environmental code) + 1900(Year and Week code)

300: Trace code

[MB85RS1MTPNF-G-AWE2] [MB85RS1MTPNF-G-AWERE2]

# RS1MT 11900 R00

[8-pin plastic SOP 150mil]

RS1MT: Product name

11900: 1(CS code) + 1900(Year and Week code)

R00: Trace code

[MB85RS1MTPNF-G-AME2] [MB85RS1MTPNF-G-AMERE2]

# RS1MT 21900 000

[8-pin plastic SOP 150mil]

RS1MT: Product name

21900: 2(CS code) + 1900(Year and Week code)

000: Trace code

[MB85RS1MTPN-G-AWEWE1]



[8-pin plastic DFN 5mm × 6mm]

MB85RS1MT: Product name

1E1: 1(CS code) + E1(Environmental code)

1900R00: 1900(Year and Week code) + R00(Trace code)

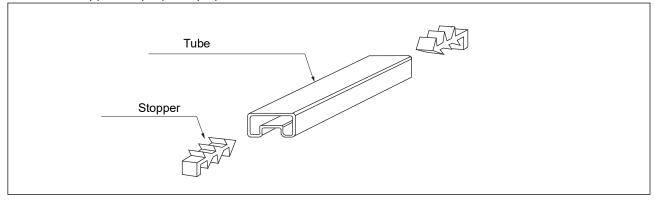
#### **■ PACKING INFORMATION**

(1)MB85RS1MTPNF-G-JNE1/MB85RS1MTPNF-G-AWE2

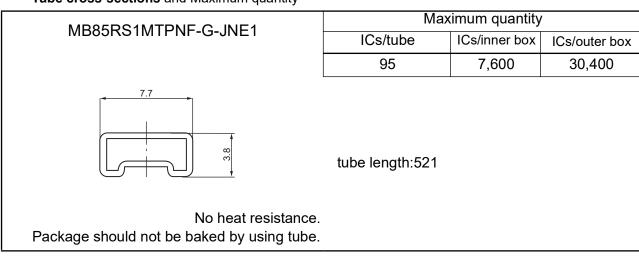
#### 1. Tube

#### 1.1 Tube Dimensions

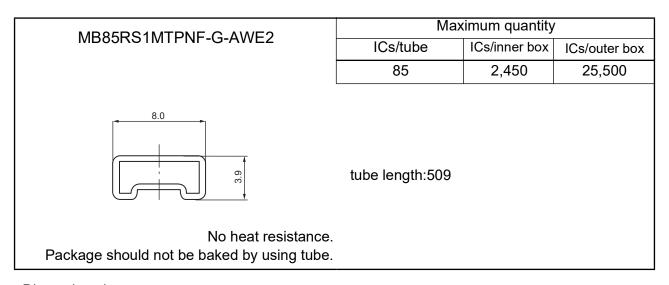
Tube/stopper shape (example)



#### • Tube cross-sections and Maximum quantity

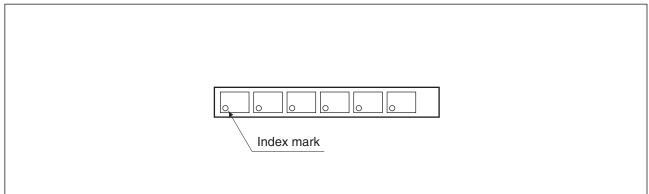


## (Dimensions in mm)



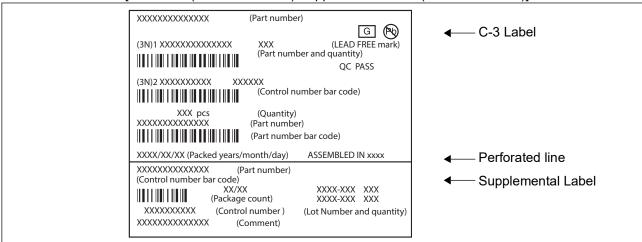
(Dimensions in mm)

· Direction of index in tube



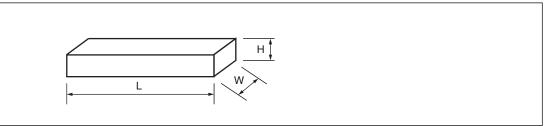
#### 1.2 Product label indicators

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label ( $50 \text{mm} \times 100 \text{mm}$ ) Supplemental Label ( $20 \text{mm} \times 100 \text{mm}$ )]



## 1.3 Dimensions for Containers

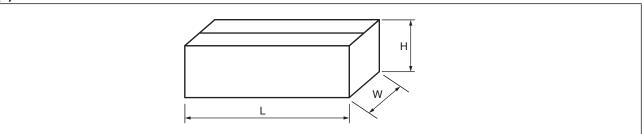
# (1) Dimensions for inner box



Part number	L	W	Н
MB85RS1MTPNF-G-JNE1	540	125	75
MB85RS1MTPNF-G-AWE2	549	125	81

(Dimensions in mm)

(2) Dimensions for outer box



Part number	L	W	Н
MB85RS1MTPNF-G-JNE1	565	270	180
MB85RS1MTPNF-G-AWE2	567	272	269

(Dimensions in mm)

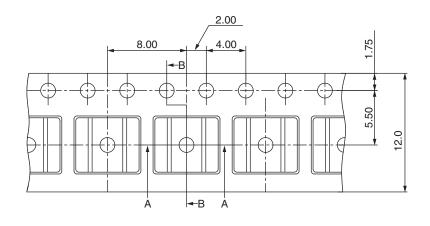
# (2)MB85RS1MTPNF-G-JNERE1/MB85RS1MTPNF-G-AWERE2/ MB85RS1MTPNF-G-AMERE2

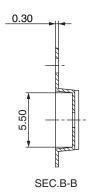
## 1. Emboss Tape

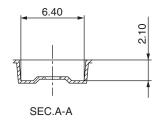
## 1.1 Tape Dimensions (not drawn to scale)(8-pin plastic SOP 150mil)

#### MB85RS1MTPNF-G-JNERE1/MB85RS1MTPNF-G-AMERE2

	reel diameter	Maximum storage capacity			MSL
Part number	(mm)	ICs/ reel	ICs/inner box	ICs/uter boxo	Label
MB85RS1MTPNF-G-JNERE1	φ330	1,500	1,500 (1 pack/inner box)	10,500 (7 inner boxes/ outer box:Max.)	No
MB85RS1MTPNF-G-AMERE2	φ254	1,500	1,500 (1 pack/inner box)	9,000 (6 inner boxes/ outer box:Max.)	No







(Dimensions in mm)

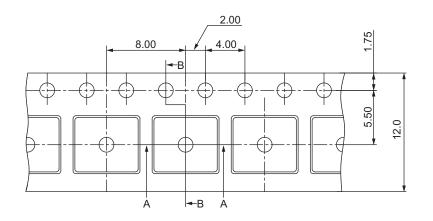
Heat proof temperature: No heat resistance.

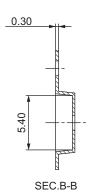
Package should not be baked by using

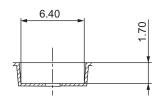
tape and reel.

## MB85RS1MTPNF-G-AWERE2

	reel diameter		MSL		
Part number	(mm) ICs/ reel		ICs/inner box	ICs/uter boxo	Label
MB85RS1MTPNF-G-AWERE2	φ330	1,500	1,500 (1 pack/inner box)	7,500 (5 inner boxes/ outer box:Max.)	Yes







(Dimensions in mm)

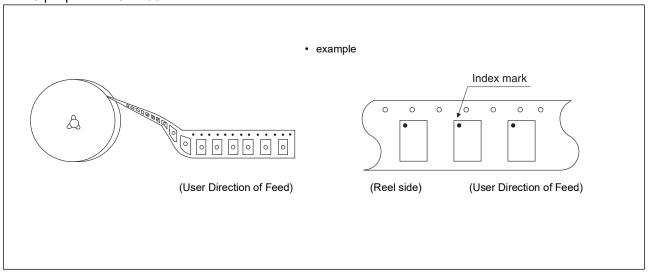
Heat proof temperature : No heat resistance.

Package should not be baked by using

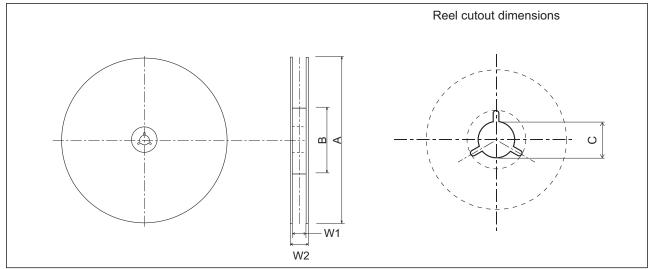
tape and reel.

## 1.2 IC orientation

8-pin plastic SOP 150mil



#### 1.3 Reel dimensions

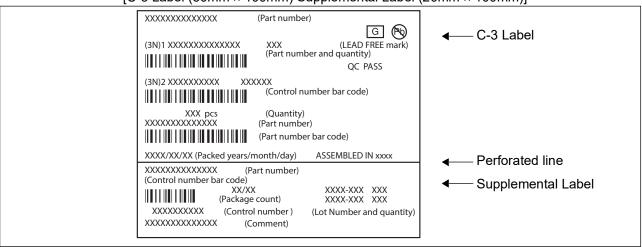


Dimensions in mm

Part number	Α	В	С	W1	W2
MB85RS1MTPNF-G-JNERE1	330	100	13	12.4	17.2
MB85RS1MTPNF-G-AWERE2	330	100	13	13.5	17.5
MB85RS1MTPNF-G-AMERE2	254	100	13	13.5	17.5

#### 1.4 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]

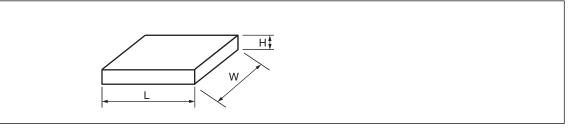


Label II:Moisture Barrier Bag (It sticks it on the Aluminum laminated bag) only for MB85RS1MTPNF-AWERE2
[MSL Label (100mm × 70mm)]



## 1.5 Dimensions for Containers

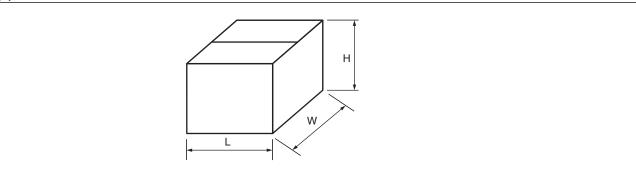
# (1) Dimensions for inner box



Part number	L	W	Н
MB85RS1MTPNF-G-JNERE1	365	345	40
MB85RS1MTPNF-G-AWERE2	350	335	35
MB85RS1MTPNF-G-AMERE2	265	260	50

(Dimensions in mm)

# (2) Dimensions for outer box



Part number	L	W	Н
MB85RS1MTPNF-G-JNERE1	415	400	315
MB85RS1MTPNF-G-AWERE2	384	368	225
MB85RS1MTPNF-G-AMERE2	565	270	180

(Dimensions in mm)

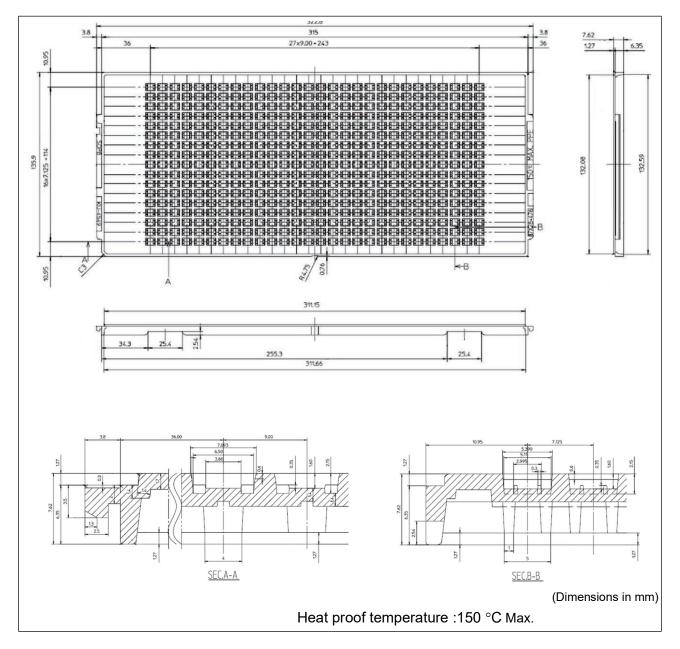
# (3)MB85RS1MTPNF-G-AME2

#### 1. Tray

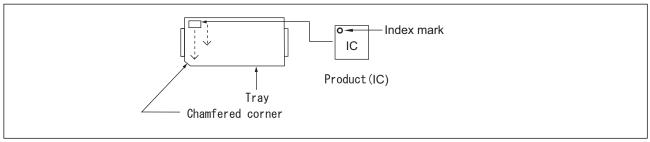
## 1.1 Tray Storage Capacity

Maximum storage capacity				
ICs/tray ICs/inner box ICs/outer box				
476	4,760 (Max:10 trays/inner box)	19,040 (Max: 4 inner boxes/outer box)		

# 1.2 Tray Dimensions (JEDEC Standard)



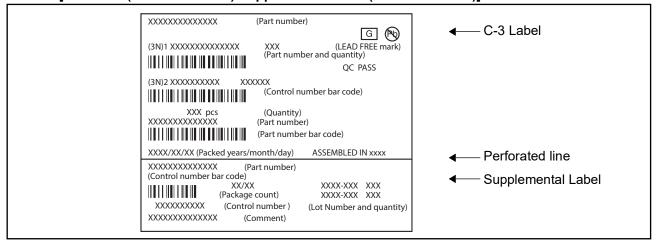
#### 1.3 IC Orientation



## 1.4 Product label indicators (an example)

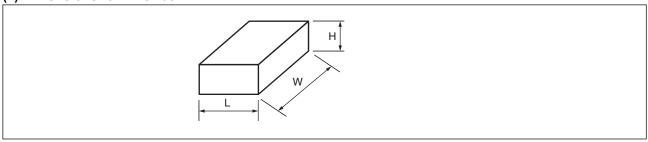
# Label on Inner box/Moisture Barrier Bag

[C-3 Label (50mm x 100mm) Supplemental Label (20mm x 100mm)]



## 1.5 Dimensions for Containers

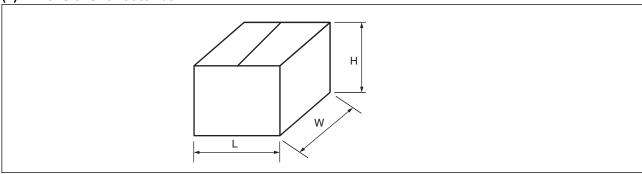
# (1) Dimensions for inner box



L	W	Н
165	360	75

(Dimensions in mm)

# (2) Dimensions for outer box



L	W	Н
355	385	195

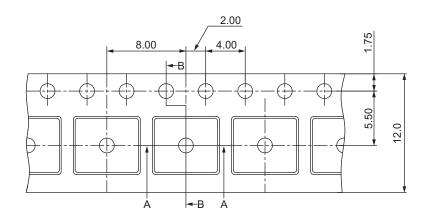
(Dimensions in mm)

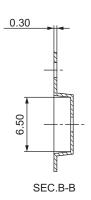
# (4)MB85RS1MTPN-G-AWEWE1

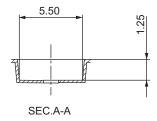
# 1. Emboss Tape

# 1.1 Tape Dimensions (not drawn to scale)(8-pin plastic DFN 5mm $\times$ 6mm)

Maximum storage capacity			
ICs/reel(φ330mm) ICs/inner box ICs/outer box		ICs/outer box	
1,500	1,500 (1 pack/inner box)	7,500 (5 inner boxes/outer box:Max.)	







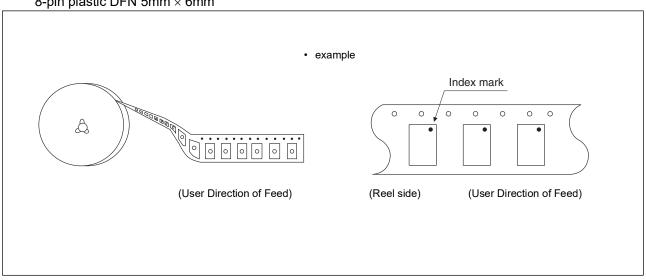
(Dimensions in mm)

Heat proof temperature : No heat resistance.

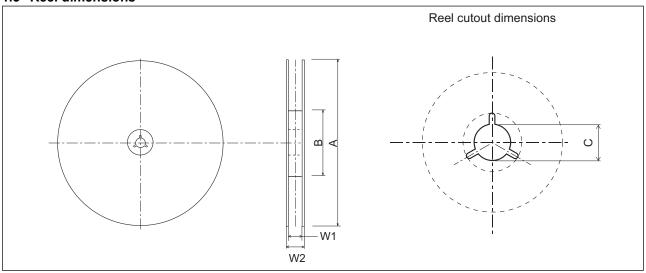
Package should not be baked by using tape and reel.

## 1.2 IC orientation

8-pin plastic DFN 5mm  $\times$  6mm



## 1.3 Reel dimensions

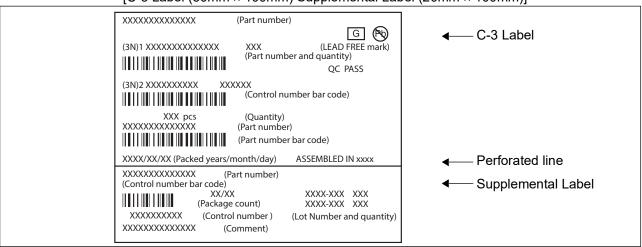


Dimensions in mm

	Α	В	С	W1	W2
DFN8	330	100	13	13.5	17.5

#### 1.4 Product label indicators (example)

Label I: Label on Inner box/Moisture Barrier Bag/ (It sticks it on the reel for the emboss taping) [C-3 Label (50mm × 100mm) Supplemental Label (20mm × 100mm)]

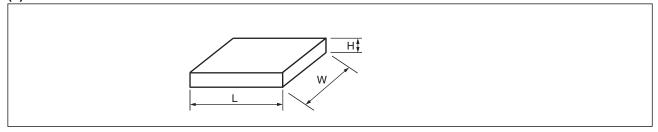


Label II:Moisture Barrier Bag (It sticks it on the Aluminum laminated bag) [MSL Label (100mm × 70mm)]



# 1.5 Dimensions for Containers

# (1) Dimensions for inner box

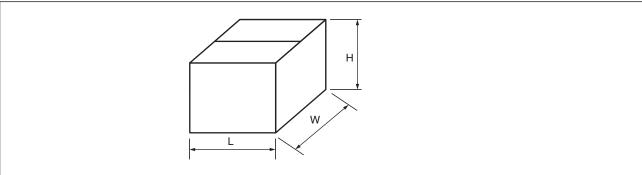


	Tape width	L	W	Н
DFN8	12	350	335	35

(Dimensions in mm)

# (2) Dimensions for outer box

38



	L	W	Н
DFN8	384	368	225

(Dimensions in mm)

# ■ MAJOR CHANGES IN THIS EDITION

A change on a page is indicated by a vertical line drawn on the left side of that page.

Page	Section	Change Results
19	■ ORDERING INFORMATION	Following new part numbers are added. MB85RS1MTPNF-G-AME2 MB85RS1MTPNF-G-AMERE2
23	■ MARKING	New part numbers' marking are added. MB85RS1MTPNF-G-AME2 MB85RS1MTPNF-G-AMERE2
27	■ PACKING INFORMATION (2)	MB85RS1MTPNF-G-AMERE2 is added.
32	■ PACKING INFORMATION (3)	MB85RS1MTPNF-G-AME2 is added.

# RAMXEED LIMITED

Shin-Yokohama Chuo Building, 2-100-45 Shin-Yokohama, Kohoku-ku, Yokohama, Kanagawa 222-0033, Japan https://ramxeed.com/

#### All Rights Reserved.

RAMXEED LIMITED, its subsidiaries and affiliates (collectively, "RAMXEED") reserves the right to make changes to the information contained in this document without notice. Please contact your RAMXEED sales representatives before order of RAMXEED device.

Information contained in this document, such as descriptions of function and application circuit examples is presented solely for reference to examples of operations and uses of RAMXEED device. RAMXEED disclaims any and all warranties of any kind, whether express or implied, related to such information, including, without limitation, quality, accuracy, performance, proper operation of the device or non-infringement. If you develop equipment or product incorporating the RAMXEED device based on such information, you must assume any responsibility or liability arising out of or in connection with such information or any use thereof. RAMX-EED assumes no responsibility or liability for any damages whatsoever arising out of or in connection with such information or any use thereof.

Nothing contained in this document shall be construed as granting or conferring any right under any patents, copyrights, or any other intellectual property rights of RAMXEED or any third party by license or otherwise, express or implied. RAMXEED assumes no responsibility or liability for any infringement of any intellectual property rights or other rights of third parties resulting from or in connection with the information contained herein or use thereof.

The products described in this document are designed, developed and manufactured as contemplated for general use including without limitation, ordinary industrial use, general office use, personal use, and household use, but are not designed, developed and manufactured as contemplated (1) for use accompanying fatal risks or dangers that, unless extremely high levels of safety is secured, could lead directly to death, personal injury, severe physical damage or other loss (including, without limitation, use in nuclear facility, aircraft flight control system, air traffic control system, mass transport control system, medical life support system and military application), or (2) for use requiring extremely high level of reliability (including, without limitation, submersible repeater and artificial satellite). RAMXEED shall not be liable for you and/or any third party for any claims or damages arising out of or in connection with above-mentioned uses of the products.

Any semiconductor devices fail or malfunction with some probability. You are responsible for providing adequate designs and safeguards against injury, damage or loss from such failures or malfunctions, by incorporating safety design measures into your facility, equipments and products such as redundancy, fire protection, and prevention of overcurrent levels and other abnormal operating conditions.

operating conditions.

The products and technical information described in this document are subject to the Foreign Exchange and Foreign Trade Control Law of Japan, and may be subject to export or import laws or regulations in U.S. or other countries. You are responsible for ensuring compliance with such laws and regulations relating to export or re-export of the products and technical information described herein. All company names, brand names and trademarks herein are property of their respective owners.